This document describes how to use and configure the frequency measurement module on LPC553x/S3x devices.
1 Introduction

The frequency measurement (FREQME) block has been introduced for LPC553x devices. This simple peripheral block can solve specific software tasks by hardware and save computation power for other application cases. This peripheral block is intended for frequency and pulse width measurement of internal and external signals.

This application note helps the user to understand this module and examples in this application note accelerate the feature evaluation.

2 Acronyms

Table 1 lists the acronyms used in this document.

<table>
<thead>
<tr>
<th>Acronym</th>
<th>Meaning</th>
</tr>
</thead>
<tbody>
<tr>
<td>FREQME</td>
<td>Frequency measurement</td>
</tr>
<tr>
<td>PWM</td>
<td>Pulse width measurement</td>
</tr>
<tr>
<td>SDK</td>
<td>Software development kit</td>
</tr>
<tr>
<td>MCU</td>
<td>Microcontroller unit</td>
</tr>
<tr>
<td>REF_CLK_IN</td>
<td>Reference clock input</td>
</tr>
<tr>
<td>TARGET_CLK_IN</td>
<td>Target clock input</td>
</tr>
</tbody>
</table>

3 FREQME module

FREQME accurately measures the frequency of an on/off-chip target clock signal using a selectable on-chip reference clock. For example, it accurately determines the frequency of a low-power oscillator that varies depending on process and temperature.

The features of the FREQME module are as follows:

- High-accuracy frequency measurement mode for on-chip and off-chip clocks
- Pulse width measurement (PWM) mode
- Reference and target clock inputs, selectable from among various chip-specific options
- Optional measurement complete interrupt
- Result of out-of-range detection with optional interrupt

4 Configuration of register

FREQME is a basic module with five registers. The main register to configure is CTRL_W. Users can use the software development kit (SDK) driver or directly write to registers using predefined masks from the device header file. If there is required manual clearing of status flags without the SDK driver, then the user has to read
the FREQMECTRLSTAT register first, then clear the required bits (for example, MEASURE_IN_PROGRESS_MASK, LT_MIN_STAT, GT_MAX_STAT), and write back to the CTRL_W register.

Examples for evaluation are created using the SDK driver. There is only one non-SDK function for setting up the reference scale at runtime.

4.1 Frequency measurement mode

In frequency measurement mode, the SDK configuration is set as shown in Equation 1:

\[
\text{configOperateMode} = \text{kFREQME_FreqMeasurementMode}
\]  \hspace{1cm} (1)

For this mode, FREQME counts the number of target clock cycles that occur during a specified number of cycles from a reference clock with a known frequency.

Calculation of target frequency is based on Equation 2:

\[
F_{\text{target}} = \left(\text{CTRL}_R[\text{RESULT}] - 2\right) \times \text{Frequency} \div 2^{\text{CTRL}_W[\text{REFSCALE}]}
\]  \hspace{1cm} (2)

The Equation 2 is implemented in the SDK function FREQME_CalculateTargetClkFreq, which is used in the software example. 12 MHz oscillator is selected as reference clock and the main system clock is selected as target clock. By setting a higher reference scale number, the target frequency is measured for longer time to get higher and more precise result.

The SDK functions FREQME_SetMinExpectedValue and FREQME_SetMaxExpectedValue are used to configure the minimum and maximum registers. FREQME module trigger interrupt or set flag when the result register is out of predefined limits. For example, the flag must be checked in some periodic event or the background loop. In the example, an interrupt-based approach is used. For starting the measurement cycle, the SDK function FREQME_StartMeasurementCycle is used and it is used each time after getting the result. In the default configuration, the example must work after build.

4.2 Pulse width measurement mode

The SDK configuration sets the pulse width mode as shown in Equation 3:

\[
\text{configOperateMode} = \text{kFREQME_PulseWidthMeasurementMode}
\]  \hspace{1cm} (3)

For this mode, the reference scale parameter is ignored. FREQME module counts reference clock pulses while the target clock is in a specific state (high or low). Polarity of the measured signal can be changed in runtime using the FREQME_SetPulsePolarity function.

In the example, the eFlexPWM module is used as a reference clock. Pulse width can be set from the FreeMASTER. This signal must be externally routed to the specific GPIO pin. Main system clock is internally routed as the target clock of FREQME input.

5 Evaluation of the examples

For project evaluation, install the latest MCUXpresso IDE and FreeMASTER real-time debugger. Although some familiarity with FreeMASTER debugging is helpful, this project is so simple that even beginners must not encounter any difficulties.

In the example, define FREQ_MEAS, which switches the code between frequency or pulse width measurement.

For pulse width measurement, connect wire from PWM output pin to FREQME input pin as it is platform-dependent, see Table 2. For frequency measurement, wire connection is not required as everything is done internally.
Table 2. Hardware signals on the EVK

<table>
<thead>
<tr>
<th>EVK board</th>
<th>Header</th>
<th>MCU port</th>
<th>MCU signal</th>
</tr>
</thead>
<tbody>
<tr>
<td>LPCXpresso55S36</td>
<td>J10-15</td>
<td>1-20</td>
<td>PWM0 A0</td>
</tr>
<tr>
<td>LPCXpresso55S36</td>
<td>J10-5</td>
<td>1-4</td>
<td>FREQME CLKA</td>
</tr>
</tbody>
</table>

To import the project into the IDE, perform the steps as follows:

1. Open `main.c` source file and set `#define FREQ_MEAS` for required operation:
   - 1 for frequency measurement
   - 0 for pulse width measurement
2. Build and flash the project.
3. Start FreeMASTER and load `FREQMEASURE_evaluation.pmx` project.
4. To run FreeMASTER communication, click the GO button.
5. Watch and set variables and observe the FreeMASTER scope.

Table 3 explains the variables used in the project. Read/write (R/W) attribute means that it is accessible from FreeMASTER.

<table>
<thead>
<tr>
<th>Variable</th>
<th>Description</th>
<th>R/W</th>
</tr>
</thead>
<tbody>
<tr>
<td><code>ui8PulsePol</code></td>
<td>Pulse polarity <code>kFREQME_PulseLowPeriod</code> or <code>kFREQME_PulseHighPeriod</code> for pulse width measurement mode.</td>
<td>RW</td>
</tr>
<tr>
<td><code>ui32FreqmeResultReg</code></td>
<td>Raw measurement result</td>
<td>R</td>
</tr>
<tr>
<td><code>ui32MeasFreq</code></td>
<td>Calculated frequency</td>
<td>R</td>
</tr>
<tr>
<td><code>ui32RefFreq</code></td>
<td>Reference frequency</td>
<td>R</td>
</tr>
<tr>
<td><code>ui32FreqMeasLoLim</code></td>
<td>Minimum register value</td>
<td>RW</td>
</tr>
<tr>
<td><code>ui32FreqMeasHiLim</code></td>
<td>Maximum register value</td>
<td>RW</td>
</tr>
<tr>
<td><code>ui32RefScale</code></td>
<td>Scale for frequency measurement. If a higher number is set, more time is required to collect the result. In extreme cases, it takes up to minutes.</td>
<td>RW</td>
</tr>
<tr>
<td><code>i16Duty</code></td>
<td>PWM duty cycle source for pulse width measurement</td>
<td>RW</td>
</tr>
<tr>
<td><code>ui32ResultOverflowCnt</code></td>
<td>Incrementing number when overflow occurs</td>
<td>R</td>
</tr>
<tr>
<td><code>ui32ResultUnderflowCnt</code></td>
<td>Incrementing number when underflow occurs</td>
<td>R</td>
</tr>
<tr>
<td><code>ui32ResultReadyCnt</code></td>
<td>Incrementing number when the result is ready</td>
<td>R</td>
</tr>
</tbody>
</table>

5.1 Troubleshooting

The examples function in the default configuration; however, some behavior can occur, especially when editing the project. The main pointer that the application runs OK is that the numbers in FreeMASTER are live, especially `ui32ResultReadyCnt` must increment.

Table 4 lists the issues and provides the solution when the application is not working correctly.

Table 4. Troubleshooting

<table>
<thead>
<tr>
<th>Issue</th>
<th>Solution</th>
</tr>
</thead>
<tbody>
<tr>
<td><code>ui32ResultReadyCnt</code> has no increment</td>
<td>In pulse width measurement mode, the wire is not connected on the EVK board from PWM output pin to FREQME input pin.</td>
</tr>
</tbody>
</table>
Table 4. Troubleshooting...continued

<table>
<thead>
<tr>
<th>Issue</th>
<th>Solution</th>
</tr>
</thead>
<tbody>
<tr>
<td>ui32ResultReadyCnt has no increment</td>
<td>Input mux to the FREQME module are not correct or source signals (clocks) are not enabled in the system.</td>
</tr>
<tr>
<td>ui32ResultReadyCnt has no increment</td>
<td>Scale set close to its limits (31) produces long waiting time until the results are ready (up to minutes). Use lower scale if you want to get the results faster.</td>
</tr>
<tr>
<td>ui32MeasFreq is 0</td>
<td>For pulse width mode, frequency calculation does not make sense so the result is 0 because ui32RefFreq is preset to 0. In frequency measurement mode, check why ui32RefFreq is not filled with reference clock value.</td>
</tr>
<tr>
<td>FreeMASTER cannot connect to the target</td>
<td>A debug session running in the MCUXpresso IDE is the most usual behavior. User must kill the debug session in the MCUXpresso IDE. It is not possible to run both debug sessions (MCUXpresso and FreeMASTER) because they access the same debug interface. It is recommended not to use the debug session for flashing instead use the flash button 🗨️. To enable the flash button in the menu bar, perform the following steps: 1. User must select the project. 2. User must kill the debug session in MCUXpresso when the conflict occurs with the debug and FreeMASTER session. 3. Unplug/plug EVK USB and restart FreeMASTER. 4. User must click the GO button to start communication.</td>
</tr>
</tbody>
</table>

6 References

Table 5 lists the resources that can be referred for more information.

Table 5. References

<table>
<thead>
<tr>
<th>Documents/resources</th>
<th>Link/how to access</th>
</tr>
</thead>
<tbody>
<tr>
<td>MCUXpresso Integrated Development Environment</td>
<td>MCUXpresso IDE</td>
</tr>
<tr>
<td>FreeMASTER Run-Time Debugging Tool</td>
<td>FreeMASTER</td>
</tr>
</tbody>
</table>

7 Revision history

Table 6 summarizes the revisions to this document.

Table 6. Revision history

<table>
<thead>
<tr>
<th>Revision number</th>
<th>Release date</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>23 August 2023</td>
<td>Initial public release</td>
</tr>
</tbody>
</table>
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